

Analysis of deep level spectrum in GaAs p⁺-p-i-n-n⁺ structures

Toompuu, Jana; Sleptšuk, Natalja; Korolkov, Oleg; Rang, Toomas Materials characterization VII 2015 / p. 283-294 : ill

Characterization of deep level traps in semiconductor structures using numerical experiments

Koel, Ants; Rang, Toomas; Rang, Galina Materials characterization VII 2015 / p. 253-261 : ill